Editorial

This issue contains several articles on new organic and mineral X-ray powder diffraction data, a technical article on a new method of indexing using classical geometry, and two articles on metal organic frameworks. Denise Flaherty has written about our most recent Denver X-ray Conference. Claudia Rawn updates us on the American Crystallographic Association's 2012 Annual Meeting. Finally, Gang Wang provides calendars of both meetings and workshops of interest that will be happening soon. We look to bring you the very best in materials characterization and hope you find these articles useful. This issue closes our first year publishing with Cambridge University Press. Next year we plan to have supplemental content from the 11th Chinese National Conference on X-ray Diffraction and publish the proceedings from the 13th European Powder Diffraction Conference (EPDIC-13).

> Nicole Ernst Boris Managing Editor